

IN THE CLAIMS:

Please amend claim 1 as follows:

1. (Twice amended) A system for inspecting a specimen, comprising:
an optical element arrangement for receiving light from a light generating device and
imparting light toward said specimen and receiving a retro beam from said specimen, said retro
beam having a retro beam diameter;
a retro beam diversion element for diverting the retro beam from said optical element
arrangement;
a multi-element sensing device for receiving and sensing retro beam position upon
diversion from said optical arrangement, said multi-element sensing device comprising [more
than two] a plurality of linearly oriented sensing [components] elements; and
a plurality of weighting elements corresponding to each of said plurality of sensing
elements, wherein each of said weighting elements alters a characteristic of an electrical output
of said corresponding sensing element based on a distance of said sensing element from a
predetermined point on said multi-element sensing device.

Please amend claim 24 as follows:

24. (Twice amended) A system for detecting contours on a specimen surface,
comprising:
application means for applying light energy to said specimen surface, said application
means comprising a light generating device and an optical element arrangement for receiving
light from said light generating device and imparting light toward said specimen surface; and
detecting means for detecting surface variations having relative surface height variations

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of less than approximately 1000 nanometers and surface contours over areas larger than particles and scratches, said detecting means comprising an optical relay for transmitting light energy received from said specimen surface and receiving a retro beam deflected therefrom and transmitting said retro beam toward a [predetermined target] multi-element sensing device comprising a plurality of linearly oriented sensing elements such that said retro beam is received by at least three of said sensing elements.

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Please amend claim 37 as follows:

37. (Twice amended) A method for inspecting a specimen, comprising [the steps of]:
providing light energy to said specimen via an arrangement of optical elements, thereby creating a retro beam reflected from said specimen;
passing said retro beam back through said arrangement of optical elements;
providing said retro beam to a multi-element sensing device, said retro beam having an expected [diversion] deflection in a substantially predetermined direction and said multi-element sensing device comprising [more than two] a plurality of linearly oriented sensing components, each of said sensing elements producing an electrical output in response to sensing a portion of said retro beam; and
altering a characteristic of said electrical output according to a weighting element corresponding to a distance of each of said plurality of sensing elements from a predetermined point on said multi-element sensing device,
wherein said sensing device senses movement of the retro beam corresponding to anomalies on said specimen.
